

May 2012
UniFET

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FDP13N50F / FDPF13N50FT N-Channel MOSFET

500V, **12A**, **0.54** Ω

Features

- $R_{DS(on)} = 0.42\Omega$ (Typ.)@ $V_{GS} = 10V$, $I_D = 6A$
- Low gate charge (Typ. 30nC)
- Low C_{rss} (Typ. 14.5pF)
- · Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- · RoHS compliant



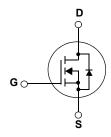
Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficient switched mode power supplies and active power factor correction.







MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter		FDP13N50F	FDPF13N50FT	Units	
V_{DSS}	Drain to Source Voltage			5	V		
V _{GSS}	Gate to Source Voltage			±30		V	
	Drain Current	-Continuous (T _C = 25°C)		12	12*	^	
ID	Drain Current	-Continuous (T _C = 100°C)		7.2	7.2*	Α	
I _{DM}	Drain Current	- Pulsed	(Note 1)	48	48*	Α	
E _{AS}	Single Pulsed Avalanche Energy (Note		(Note 2)	684		mJ	
I _{AR}	Avalanche Current		(Note 1)	12		Α	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	19.5		mJ	
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20		V/ns	
D	Dower Dissipation	$(T_C = 25^{\circ}C)$		195	42	W	
P_{D}	Power Dissipation	- Derate above 25°C		1.53	0.33	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150		οС		
TL	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			3	300	°C	

^{*}Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter	FDP13N50F	FDPF13N50FT	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.65	3.0	
$R_{\theta CS}$	Thermal Resistance, Case to Sink Typ.	0.5	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	62.5	62.5	

Package Marking and Ordering Information $T_C = 25^{\circ}C$ unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDP13N50F	FDP13N50F	TO-220	-	-	50
FDPF13N50FT	FDPF13N50FT	TO-220F	-	-	50

Electrical Characteristics

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Charac	cteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$, $V_{GS} = 0V$, $T_J = 25^{\circ}C$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I _D = 250μA, Referenced to 25°C	-	0.7	-	V/°C
	Zoro Coto Voltago Drain Current	V _{DS} = 500V, V _{GS} = 0V	-	-	10	^
I _{DSS} Zero Gate Voltage Drain Current	$V_{DS} = 400V, T_C = 125^{\circ}C$	-	-	100	μΑ	
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	V_{GS} = 10V, I_D = 6A	-	0.42	0.54	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = 20V, I_D = 6A$ (Note 4)	-	13.3	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	\\ - 25\\ \\ - 2\\	-	1450	1930	pF
C _{oss}	Output Capacitance	V _{DS} = 25V, V _{GS} = 0V f = 1MHz	-	198	265	pF
C _{rss}	Reverse Transfer Capacitance		-	14.5	22	pF
Q _{g(tot)}	Total Gate Charge at 10V		-	30	39	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DS} = 400V, I_{D} = 13A$	-	8	-	nC
Q _{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10V (Note 4, 5)	1	12	-	nC

Switching Characteristics

t _{d(on)}	Turn-On Delay Time			-	28	65	ns
t _r	Turn-On Rise Time	$V_{DD} = 250V, I_D = 13A$		-	54	120	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25\Omega$		-	75	160	ns
t _f	Turn-Off Fall Time		(Note 4, 5)	-	47	105	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	12	Α	
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	48	Α	
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 12A		-	-	1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0V, I _{SD} = 12A		-	154	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100A/\mu s$	(Note 4)	-	0.45	-	μС

^{1.} Repetitive Rating: Pulse width limited by maximum junction temperature

^{2.} L = 9.5mH, I_{AS} = 12A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25 $^{\circ}$ C

^{3.} I $_{SD}$ \leq 12A, di/dt \leq 200A/ μ s, V $_{DD}$ \leq BV $_{DSS}$, Starting T $_{J}$ = 25°C

^{4.} Pulse Test: Pulse width $\leq 300 \mu s, \, \text{Duty Cycle} \leq 2\%$

^{5.} Essentially Independent of Operating Temperature Typical Characteristics

Typical Performance Characteristics

Figure 1. On-Region Characteristics

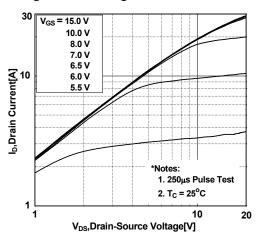


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

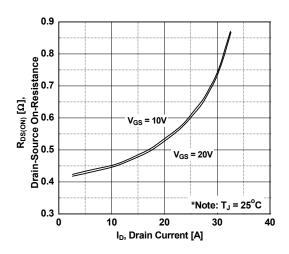


Figure 5. Capacitance Characteristics

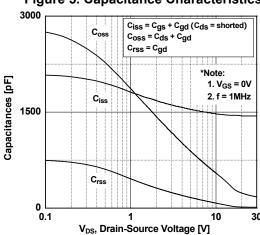


Figure 2. Transfer Characteristics

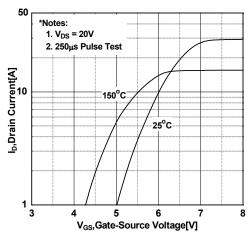


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

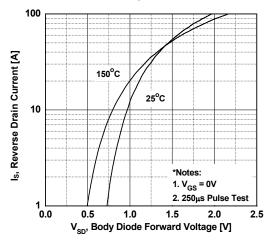
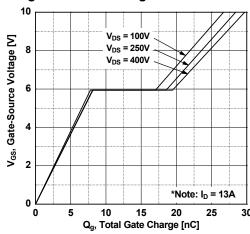


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

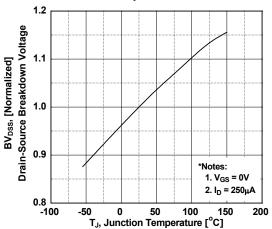


Figure 8. Maximum Safe Operating Area - FDPF13N50FT

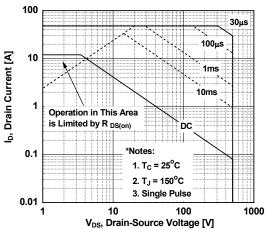


Figure 9. Maximum Drain Current vs. Case Temperature

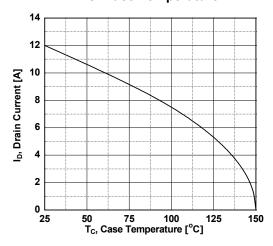
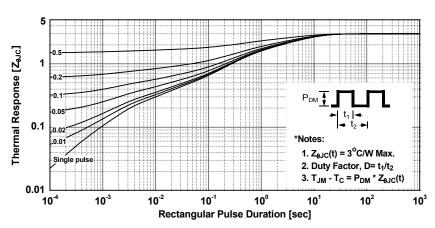
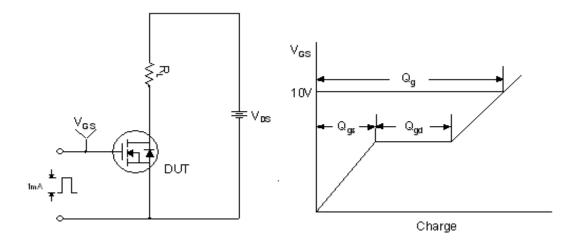


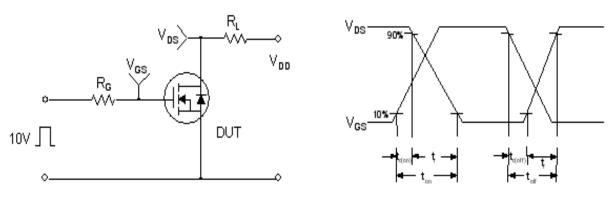
Figure 10. Transient Thermal Response Curve - FDPF13N50FT



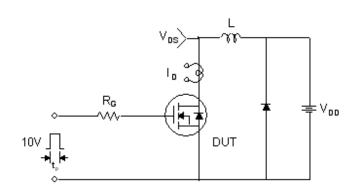
Gate Charge Test Circuit & Waveform

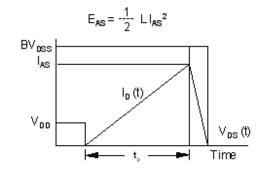


Resistive Switching Test Circuit & Waveforms

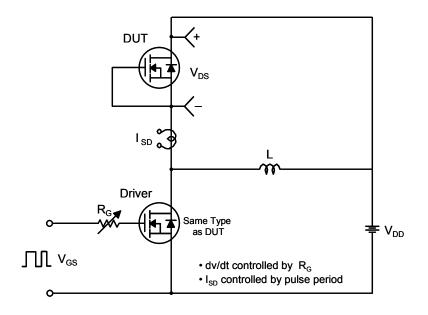


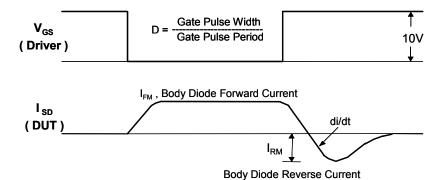
Unclamped Inductive Switching Test Circuit & Waveforms

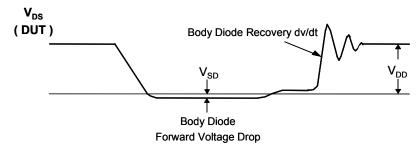




Peak Diode Recovery dv/dt Test Circuit & Waveforms

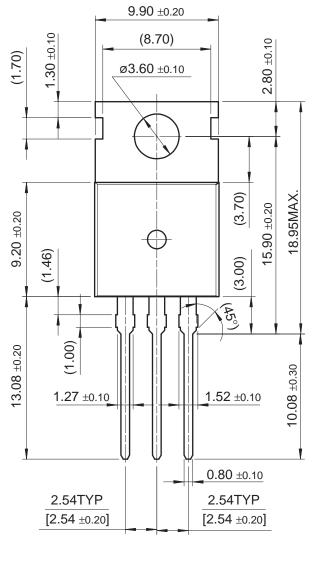


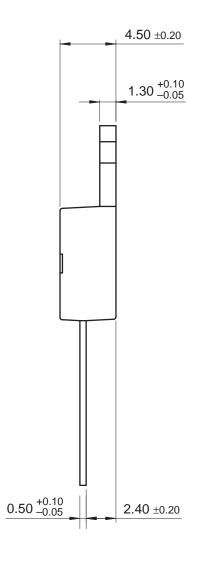


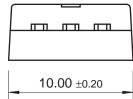


Mechanical Dimensions

TO-220

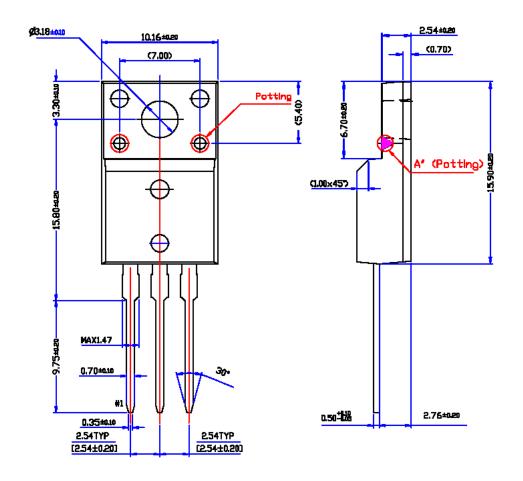


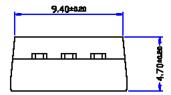




Package Dimensions

TO-220F Potted





* Front/Back Side Isolation Voltage : AC 2500V

Dimensions in Millimeters





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